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June 2016

FDD7N25LZ

N-Channel UniFETTM MOSFET 250 V, 6.2 A, 550 m Ω

Features

- $R_{DS(on)}$ = 430 m Ω (Typ.) @ V_{GS} = 10 V, I_D = 3.1 A
- Low Gate Charge (Typ. 12 nC)
- Low C_{rss} (Typ. 8 pF)
- · 100% Avalanche Tested
- · Improved dv/dt Capability
- · ESD Improved Capability
- · RoHS Compliant

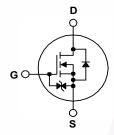
Applications

- LCD/LED/PDP TV
- · Consumer Appliances
- Lighting
- · Uninterruptible Power Supply
- AC-DC Power Supply

Description

UniFETTM MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		Parameter		FDD7N25LZTM	Unit	
V _{DSS}	Drain to Source Voltage	to Source Voltage		250	V	
V_{GSS}	Gate to Source Voltage			±20	V	
	Drain Current	- Continuous (T _C = 25°C)		6.2	_	
ID	Diam Current	- Continuous (T _C = 100°C)		3.7	Α	
I _{DM}	Drain Current	- Pulsed	(Note 1)	25	Α	
E _{AS}	Single Pulsed Avalanche Ener	ЭУ	(Note 2)	115	mJ	
I _{AR}	Avalanche Current		(Note 1)	5.5	Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	5.6	mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	10	V/ns	
D	Dawer Dissipation	(T _C = 25°C)		56	W	
P_{D}	Power Dissipation	- Derate Above 25°C		0.45	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C	
TL	Maximum Lead Temperature f	or Soldering, 1/8" from Case for 5	Seconds	300	°C	

Thermal Characteristics

Symbol	Parameter	FDD7N25LZTM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	2.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	110	*C/VV

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDD7N25LZTM	FDD7N25LZ	DPAK	Tape and Reel	330 mm	16 mm	2500 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_C = 25^{\circ} C$	250	-	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C	-	0.25	-	V/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 250 V, V _{GS} = 0 V	-	-	1	μА
I _{DSS}	Zelo Gale Voltage Diam Guilent	$V_{DS} = 200 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	10	μΑ
I _{GSSF}	Gate to Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V	-	-	10	μΑ
I _{GSSR}	Gate to Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V	-	-	-10	μΑ

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	1.0	-	2.5	V
D	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 3.1 A	-	0.43	0.55	Ω
R _{DS(on)}	Static Diam to Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 3.1 \text{ A}$	-	0.45	0.57	52
9 _{FS}	Forward Transconductance	$V_{DS} = 20 \text{ V}, I_{D} = 3.1 \text{ A}$	-	7	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05.V.V 0.V	-\	480	635	pF
C _{oss}	Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	- \	65	85	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/2	-	8	12	pF
Q _{g(tot)}	Total Gate Charge at 10V	V _{DS} = 250 V I _D = 6.2 A,	-	12	16	nC
Q _{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	1.5	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	4	-	nC

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		-	10	30	ns
t _r	Turn-On Rise Time	$V_{DD} = 250 \text{ V}, I_D = 6.2 \text{ A},$	-	15	40	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_G = 25 Ω	- /	75	160	ns
t _f	Turn-Off Fall Time	(Note 4)	-	30	70	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current			-	6.2	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	25	Α
V_{SD}	Drain to Source Diode Forward Voltage V _{GS} = 0 V, I _{SD} = 6.2 A		-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 6.2 A,	-	130	-	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt = 100 A/μs	-	0.6	-	μC

Notes:

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
- 2. L = 6 mH, I $_{AS}$ = 6.2 A, V $_{DD}$ = 50 V, R $_{G}$ = 25 $\Omega,$ starting T $_{J}$ = 25 $^{\circ}C.$
- 3. $I_{SD} \le 6.2$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, starting T_J = 25°C.
- 4. Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

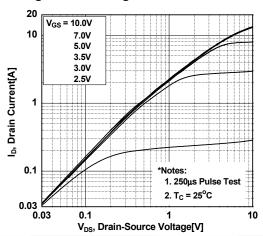


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

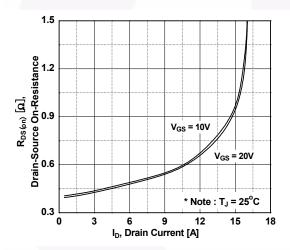


Figure 5. Capacitance Characteristics

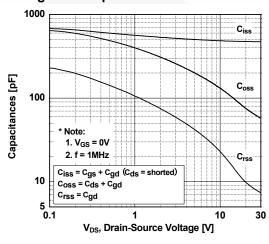


Figure 2. Transfer Characteristics

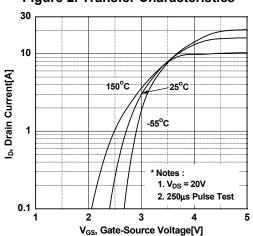


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

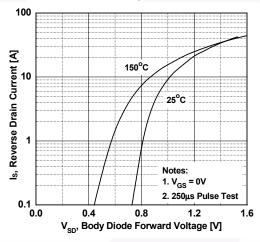
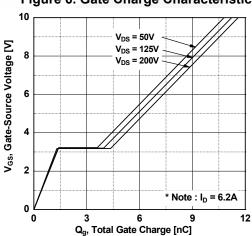


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

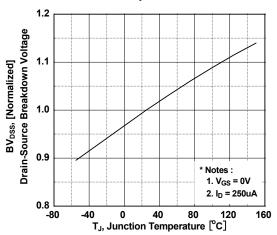


Figure 9. Maximum Safe Operating Area

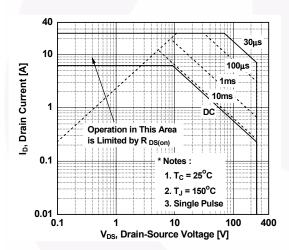


Figure 8. On-Resistance Variation vs. Temperature

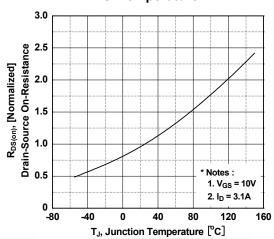


Figure 10. Maximum Drain Current vs. Case Temperature

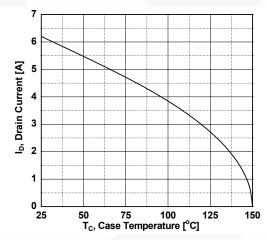
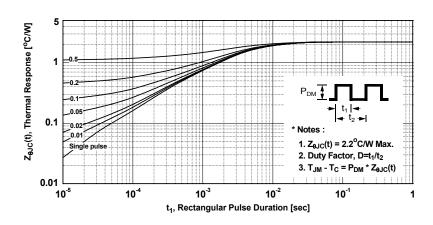


Figure 11. Transient Thermal Response Curve



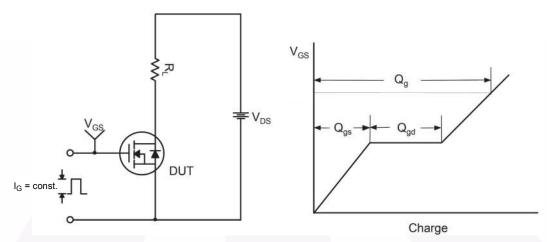


Figure 12. Gate Charge Test Circuit & Waveform

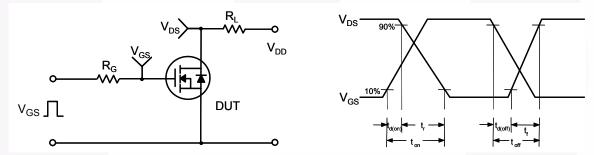


Figure 13. Resistive Switching Test Circuit & Waveforms

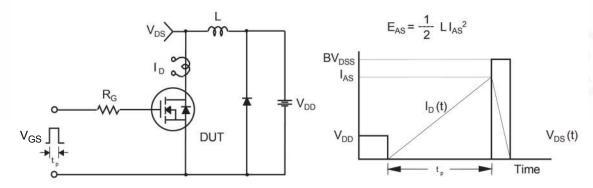


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

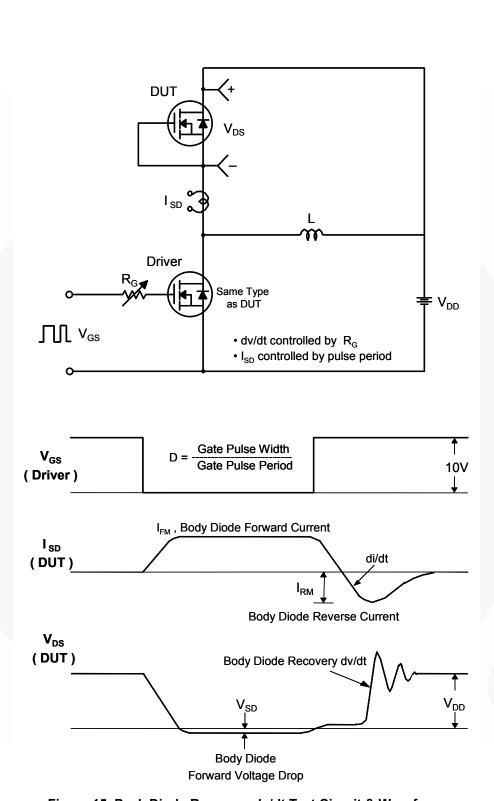
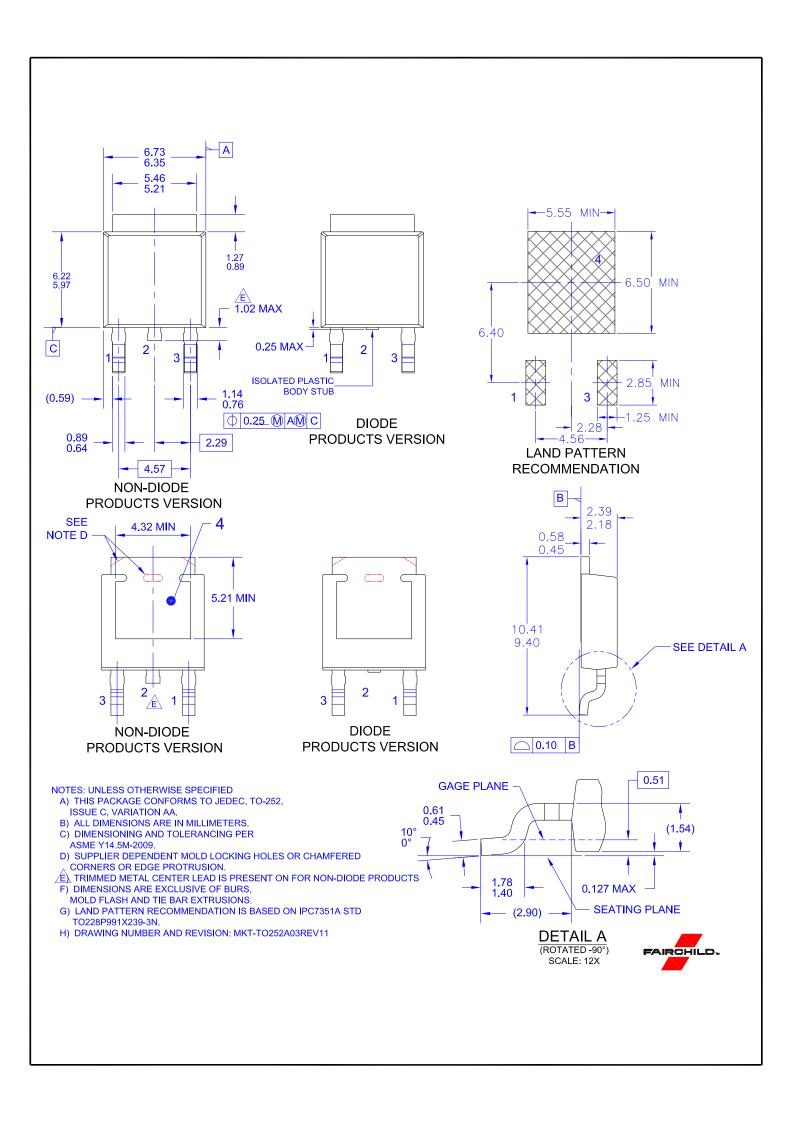


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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